eGaN® FET DATASHEET **EPC2012C** 

# **EPC2012C – Enhancement Mode Power Transistor**

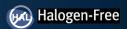
 $V_{DS}$ , 200 V $R_{DS (on)}$  ,  $100 \, m\Omega$  $I_D$ , 5A

 $R_{\theta JC}$  $R_{\theta J\underline{B}}$ 









Gallium Nitride's exceptionally high electron mobility and low temperature coefficient allows very low R<sub>DS(on)</sub>, while its lateral device structure and majority carrier diode provide exceptionally low Q<sub>G</sub> and zero Q<sub>RR</sub>. The end result is a device that can handle tasks where very high switching frequency, and low on-time are beneficial as well as those where on-state losses dominate.

	Maximum Ratings					
	PARAMETER VALUE UNI					
V <sub>DS</sub>	Drain-to-Source Voltage (Continuous)	200	V			
	Continuous ( $T_A = 25$ °C, $R_{\theta JA} = 26$ °C/W)	5	Δ			
I <sub>D</sub>	Pulsed (25°C, $T_{PULSE} = 300 \mu s$ )	22	Α			
W	Gate-to-Source Voltage	6				
V <sub>GS</sub>	Gate-to-Source Voltage	-4	V			
TJ	Operating Temperature	-40 to 150	- °C			
T <sub>STG</sub>	Storage Temperature	-40 to 150				

Maximum natings						
	PARAMETER	VALUE	UNIT			
$V_{\mathrm{DS}}$	Drain-to-Source Voltage (Continuous)	200	V			
	Continuous ( $T_A = 25$ °C, $R_{\theta JA} = 26$ °C/W)	5	^			
I <sub>D</sub>	Pulsed (25°C, $T_{PULSE} = 300 \mu s$ )	22	Α			
V	Gate-to-Source Voltage	6	V			
$V_{GS}$	Gate-to-Source Voltage	-4	V			
Tر	Operating Temperature	-40 to 150	°C			
$T_{STG}$	Storage Temperature	-40 to 150				
,						

Thermal Characteristics				
PARAMETER	ТҮР	UNIT		
Thermal Resistance, Junction-to-Case	4.2			
Thermal Resistance, Junction-to-Board	12.5	°C/W		
Thermal Resistance, Junction-to-Ambient (Note 1)	85	]		

Note 1: R<sub>8JA</sub> is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board. See https://epc-co.com/epc/documents/product-training/Appnote\_Thermal\_Performance\_of\_eGaN\_FETs.pdf for details.



EPC2012C eGaN® FETs are supplied only in passivated die form with solder bars

#### **Applications**

- High Frequency DC-DC Conversion
- · Class D Audio
- · Wireless Power Transfer

#### **Benefits**

- · Ultra High Efficiency
- Ultra Low R<sub>DS(on)</sub>
- Ultra Low  $Q_{\mathsf{G}}$
- · Ultra Small Footprint



Static Characteristics ( $T_J = 25^{\circ}$ C unless otherwise stated)						
PARAMETER TEST CONDITIONS MIN TYP MAX UNIT						UNIT
BV <sub>DSS</sub>	Drain-to-Source Voltage	$V_{GS} = 0 \text{ V, I}_{D} = 60  \mu\text{A}$	200			V
I <sub>DSS</sub>	Drain-Source Leakage	$V_{GS} = 0 \text{ V}, V_{DS} = 160 \text{ V}$		10	50	μΑ
I <sub>GSS</sub>	Gate-to-Source Forward Leakage	$V_{GS} = 5 V$		0.2	1	mA
	Gate-to-Source Reverse Leakage	$V_{GS} = -4 V$		10	50	μΑ
V <sub>GS(TH)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	0.8	1.4	2.5	V
R <sub>DS(on)</sub>	Drain-Source On Resistance	$V_{GS} = 5 \text{ V}, I_D = 3 \text{ A}$		70	100	mΩ
V <sub>SD</sub>	Source-Drain Forward Voltage	$I_S = 0.5 \text{ A}, V_{GS} = 0 \text{ V}$		1.9		V

All measurements were done with substrate connected to source.

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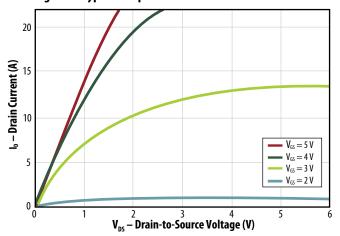
	Dynamic Characteristics (T <sub>J</sub> = 25°C unless otherwise stated)						
	PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT	
$C_{ISS}$	Input Capacitance			100	140		
$C_{RSS}$	Reverse Transfer Capacitance	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		0.4	0.6	pF	
$C_{OSS}$	Output Capacitance			64	85		
$R_{G}$	Gate Resistance			0.6		Ω	
$Q_{G}$	Total Gate Charge	$V_{DS} = 100 \text{ V}, V_{GS} = 5 \text{ V}, I_D = 3 \text{ A}$		1	1.3		
$Q_{GS}$	Gate-to-Source Charge			0.3			
$Q_{GD}$	Gate-to-Drain Charge	$V_{DS} = 100 \text{ V}, I_D = 3 \text{ A}$		0.2	0.35	nC	
$Q_{G(TH)}$	Gate Charge at Threshold			0.2		IIC IIC	
Qoss	Output Charge	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$		10	13		
$Q_{RR}$	Source-Drain Recovery Charge			0			

All measurements were done with substrate connected to source.

Note 2:  $C_{OSS(ER)}$  is a fixed capacitance that gives the same stored energy as  $C_{OSS}$  while  $V_{DS}$  is rising from 0 to 50% BV<sub>DSS</sub>.

Note 3: C<sub>OSS(TR)</sub> is a fixed capacitance that gives the same charging time as C<sub>OSS</sub> while V<sub>DS</sub> is rising from 0 to 50% BV<sub>DSS</sub>.

Figure 1: Typical Output Characteristics at 25°C



**Figure 2: Transfer Characteristics** 

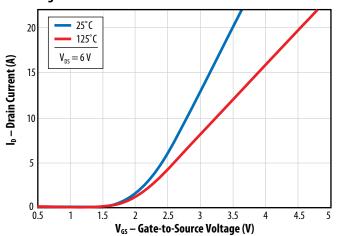


Figure 3:  $R_{DS(on)}$  vs.  $V_{GS}$  for Various Drain Currents

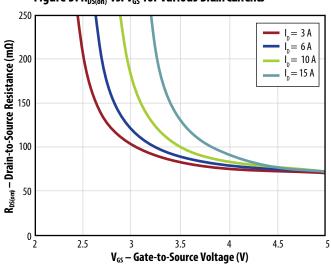
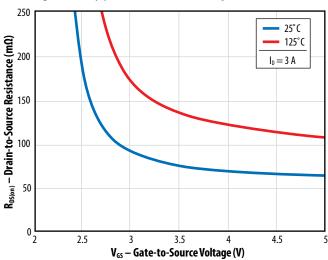
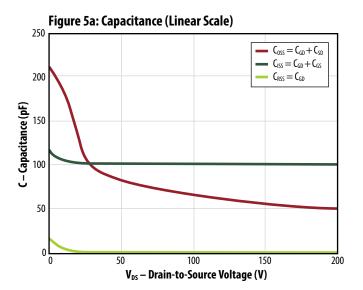
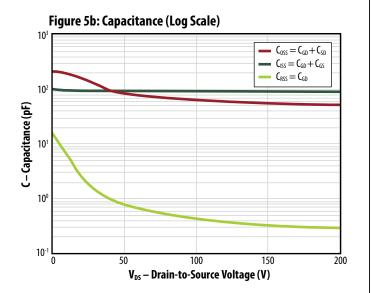


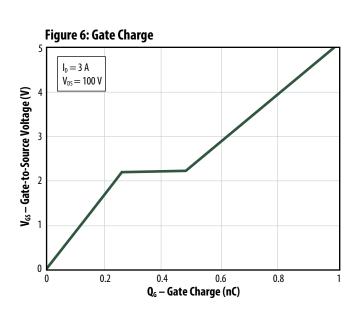
Figure 4: R<sub>DS(on)</sub> vs. V<sub>GS</sub> for Various Temperatures

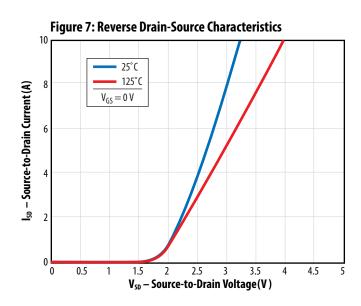


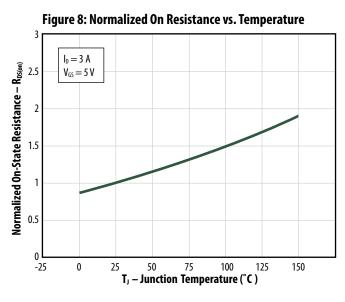
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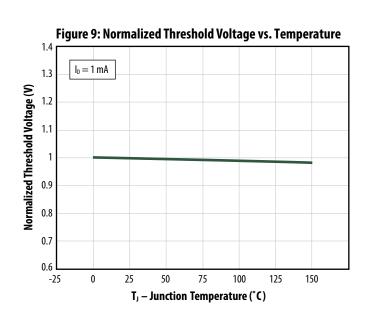






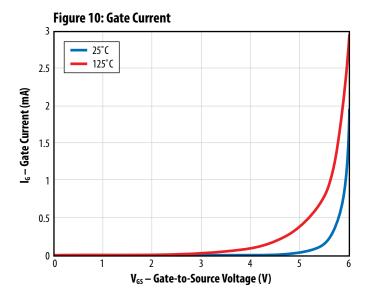




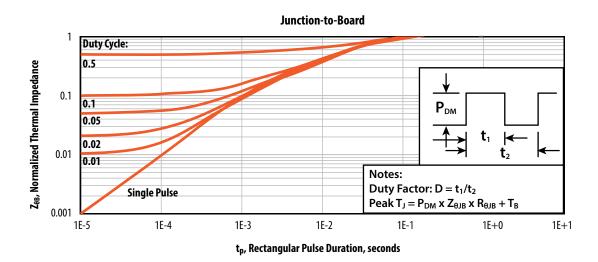


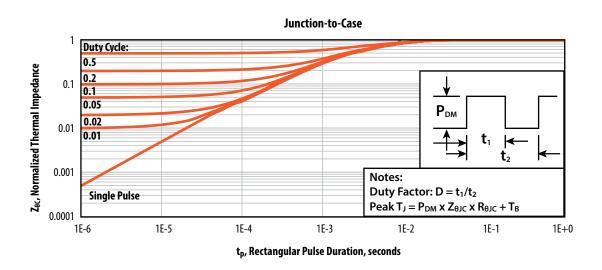
All measurements were done with substrate shortened to source.

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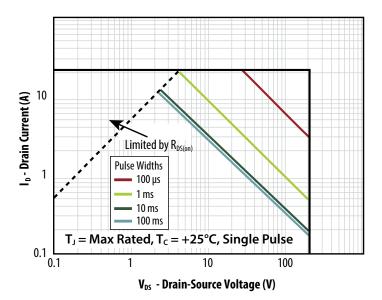
**Figure 11: Transient Thermal Response Curves** 



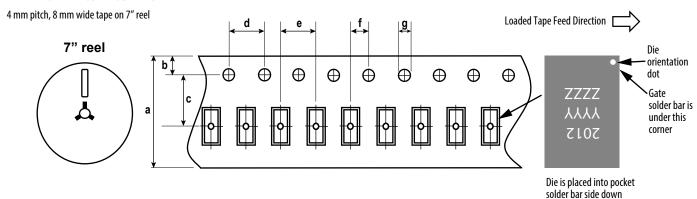


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Figure 12: Safe Operating Area



### **TAPE AND REEL CONFIGURATION**

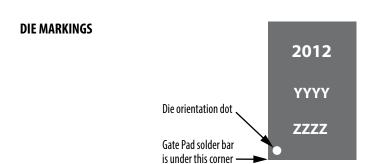


	EPC2012C (note 1)			
Dimension (mm)	target	min	max	
a	8.00	7.90	8.30	
b	1.75	1.65	1.85	
c (note 2)	3.50	3.45	3.55	
d	4.00	3.90	4.10	
е	4.00	3.90	4.10	
f (note 2)	2.00	1.95	2.05	
g	1.5	1.5	1.6	

Note 1: MSL 1 (moisture sensitivity level 1) classified according to IPC/JEDEC industry standard.

Note 2: Pocket position is relative to the sprocket hole measured as true position of the pocket, not the pocket hole.

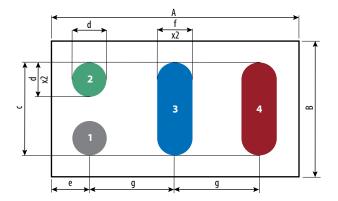
(face side down)



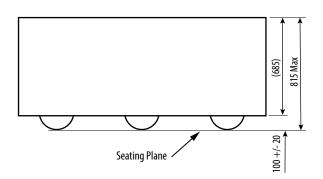
Dout	Laser Markings			
Part Number	Part # Marking Line 1	Lot_Date Code Marking line 2	Lot_Date Code Marking Line 3	
EPC2012C	2012	YYYY	ZZZZ	

## **DIE OUTLINE**

Solder Bar View



Side View



DIM	MICROMETERS			
DIM	MIN	Nominal	MAX	
A	1681	1711	1741	
В	889	919	949	
C	662	667	672	
d	245	250	255	
e	230	245	260	
f	245	250	255	
g	600 600 600		600	

Pad no. 1 is Gate;

Pad no. 2 is Substrate;\*

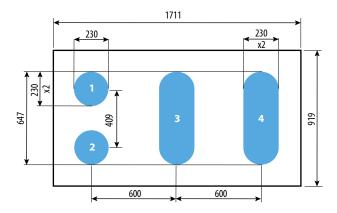
Pad no. 3 is Drain;

Pad no. 4 is Source

\*Substrate pin should be connected to Source

## **RECOMMENDED LAND PATTERN**

(units in  $\mu$ m)



The land pattern is solder mask defined.

Pad no. 1 is Gate;

Pad no. 2 is Substrate;\*

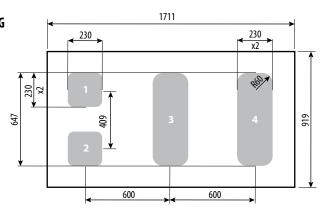
Pad no. 3 is Drain;

Pad no. 4 is Source

\*Substrate pin should be connected to Source

## **RECOMMENDED STENCIL DRAWING**

(units in  $\mu$ m)



Recommended stencil should be 4 mil (100 µm) thick, must be laser cut, opening per drawing. The corner has a radius of R60.

Intended for use with SAC305 Type 3 solder, reference 88.5% metals content.

Additional assembly resources available at https://www.epc-co.com/epc/DesignSupport/ AssemblyBasics.aspx

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